

844.

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10035349	FILING DATE 10/19/2001	CLASS 435	SUBCLASS 6	GAU 4829	EXAMINER Chakrabarti
**APPLICANTS: Schneider Luke; Hail Michael; Petesch Robert;					
**CONTINUING DATA VERIFIED: THIS APPLN CLAIMS BENEFIT OF 60/242,165 10/19/2000 AND CLAIMS BENEFIT OF 60/242,398 10/19/2000.					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO 020444-000710US	
Verified and Acknowledged Examiners's initials					
TITLE : Mass defect labeling for the determination of oligomer sequences					
U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner		CLAIMS ALLOWED	
				Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner		DRAWING	
Amount Due	Date Paid			Sheets Drwg.	Figs. Drwg.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE		Application Examiner	
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